

Data Sheet

August 2004

50A, 50V, 0.022 Ohm, Logic Level, N-Channel Power MOSFETs

These are logic-level N-channel power MOSFETs manufactured using the MegaFET process. This process, which uses feature sizes approaching those of LSI integrated circuits gives optimum utilization of silicon, resulting in outstanding performance. They were designed for use with logic-level (5V) driving sources in applications such as programmable controllers, automotive switching, switching regulators, switching converters, motor relay drivers and emitter switches for bipolar transistors. This performance is accomplished through a special gate oxide design which provides full rated conductance at gate bias in the 3V - 5V range, thereby facilitating true on-off power control directly from integrated circuit supply voltages.

Formerly developmental type TA09872.

Ordering Information

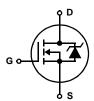
PART NUMBER	PACKAGE	BRAND	
RFP50N05L	TO-220AB	F50N05L	

NOTE: When ordering, use the entire part number. Add the suffix 9A to obtain the TO-263AB variant in the tape and reel, i.e., RFP50N05L9A.

Features

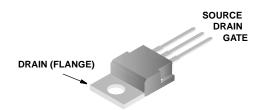
- 50A, 50V
- $r_{DS(ON)} = 0.022\Omega$
- UIS SOA Rating Curve (Single Pulse)
- · Design Optimized for 5V Gate Drive
- · Can be Driven Directly from CMOS, NMOS, TTL Circuits
- Compatible with Automotive Drive Requirements
- · SOA is Power Dissipation Limited
- · Nanosecond Switching Speeds
- Linear Transfer Characteristics
- High Input Impedance
- · Majority Carrier Device
- Related Literature
 - TB334 "Guidelines for Soldering Surface Mount Components to PC Boards"

Symbol



Packaging

JEDEC TO-220AB



RFP50N05L

Absolute Maximum Ratings $T_C = 25^{\circ}C$, Unless Otherwise Specified

	RFP50N05L	UNITS
Drain to Source Voltage (Note 1)V _{DS}	50	V
Drain to Gate Voltage ($R_{GS} = 20k\Omega$) (Note 1)V _{DGR}	50	V
Continuous Drain Current	50 130	A A
Gate to Source Voltage	±10	V
$\label{eq:maximum Power Dissipation} \begin{tabular}{ll} Maximum Power Dissipation & P_D \\ Above T_C = 25^0 C, Derate Linearly & & & & & \\ \end{tabular}$	110 0.88	W/ _o C
Single Pulse Avalanche Energy Rating	Refer to UIS SOA Curve	-
Operating and Storage Temperature	-55 to 150	°C
Maximum Temperature for Soldering Leads at 0.063in (1.6mm) from Case for 10sT _L Package Body for 10s, See Techbrief 334T _{pkg}	300 260	°C °C

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTE:

1. $T_J = 25^{\circ}C$ to $125^{\circ}C$.

Electrical Specifications $T_C = 25^{\circ}C$, Unless Otherwise Specified

Drain to Source Breakdown Voltage BVDSS ID = 250μA, VGS = 0V (Figure 10) 50 - Gate Threshold Voltage VGS(TH) VGS(TH) VGS = VDS, ID = 250μA (Figure 9) 1 - Zero Gate Voltage Drain Current IDSS VDS = Rated BVDSS, VGS = 0 - - - VDS = 0.8 x Rated BVDSS, VGS = 0, TC = 150°C - - - - Gate to Source Leakage Current IGSS VGS = ±10V, VDS = 0V - - - Drain to Source On Resistance (Note 2) TDS(ON) ID = 50A, VGS = 5V (Figure 7) - - - Turn-On Time t(ON) VGS = 5V, RGS = 2.5Ω, RL = 1Ω (Figures 12, 15, 16) - - - Turn-On Delay Time tp(OFF) - - - - - Fall Time tf tg - - - - - - Turn-Off Time t(OFF) - - - - - - - - - - - - - - -	- 2 25 250 ±100 0.022 0.027	V V μΑ μΑ nA
	25 250 ±100 0.022	μA μA nA
$V_{DS} = 0.8 \text{ x Rated BV}_{DSS}, V_{GS} = 0, T_{C} = 150^{\circ}\text{C} \qquad - \qquad $	250 ±100 0.022	μA nA
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	±100	nA
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	0.022	
		Ω
Turn-On Time $t_{(ON)}$ $V_{GS} = 5V$, $R_{GS} = 2.5\Omega$, $R_L = 1\Omega$ - - <t< td=""><td>0.027</td><td></td></t<>	0.027	
Turn-On Delay Time tD(ON) Rise Time tr Turn-Off Delay Time tD(OFF) Fall Time tf		Ω
Turn-On Delay Time tD(ON) - 15 Rise Time tr - 50 Turn-Off Delay Time tD(OFF) - 50 Fall Time tf - 15	100	ns
Turn-Off Delay Time t _D (OFF) Fall Time t _f	-	ns
Fall Time t _f - 15	-	ns
	-	ns
Turn-Off Time t _(OFF)	-	ns
	100	ns
Total Gate Charge $ Q_{G(TOT)} V_{GS} = 0 \text{ to } 10V \qquad \qquad V_{DD} = 40V, \ I_D = 50A \qquad - \qquad $	140	nC
Gate Charge at 5V $Q_{G(5)}$ $V_{GS} = 0$ to 5V $R_L = 0.8\Omega$ (Figures 17, 18)	80	nC
Threshold Gate Charge $Q_{G(th)}$ $V_{GS} = 0$ to 1V	6	nC
Thermal Resistance Junction to Case $R_{ heta JC}$	1.14	°C/W
Thermal Resistance Junction to Ambient $R_{\theta JA}$	80	°C/W

Source to Drain Diode Specifications

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNITS
Source to Drain Diode Voltage (Note 2)	V_{SD}	I _{SD} = 50A	-	-	1.5	V
Diode Reverse Recovery Time	t _{rr}	$I_{SD} = 50A$, $dI_{SD}/dt = 100A/\mu s$	-	-	1.25	ns

RFP50N05L Rev. C

NOTES:

- 2. Pulsed: pulse duration = $300\mu s$ maximum, duty cycle = 2%.
- 3. Repititive rating: pulse width limited by maximum junction temperature.

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Typical Performance Curves

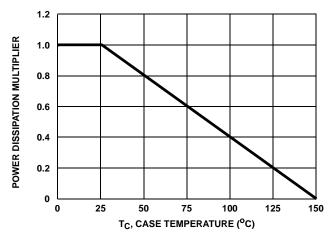


FIGURE 1. NORMALIZED POWER DISSIPATION vs CASE TEMPERATURE

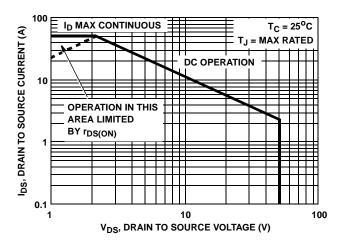


FIGURE 3. FORWARD BIAS SAFE OPERATING AREA

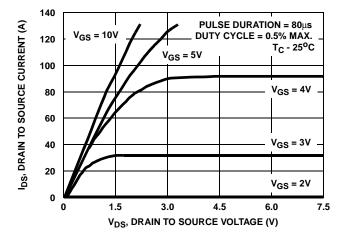


FIGURE 5. SATURATION CHARACTERISTICS

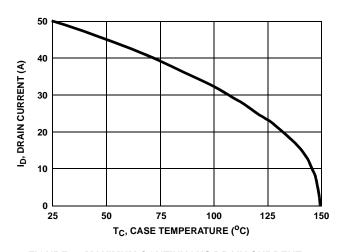


FIGURE 2. MAXIMUM CONTINUOUS DRAIN CURRENT vs CASE TEMPERATURE

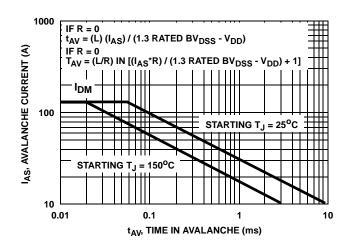


FIGURE 4. UNCLAMPED INDUCTIVE SWITCHING SAFE OPERATING AREA

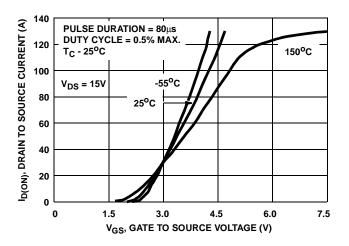


FIGURE 6. TRANSFER CHARACTERISTICS

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Typical Performance Curves (Continued)

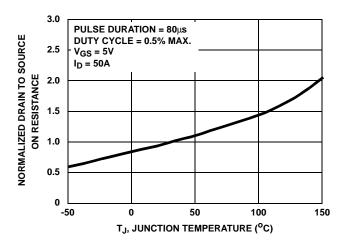


FIGURE 7. NORMALIZED DRAIN TO SOURCE ON RESISTANCE vs JUNCTION TEMPERATURE

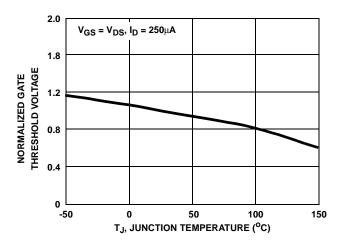


FIGURE 9. NORMALIZED GATE THRESHOLD VOLTAGE

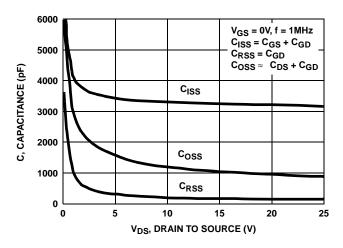


FIGURE 11. CAPACITANCE vs DRAIN TO SOURCE VOLTAGE

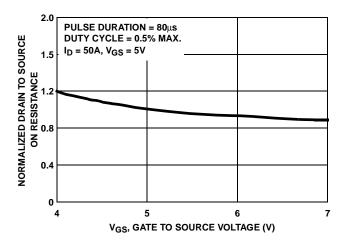


FIGURE 8. NORMALIZED DRAIN TO SOURCE ON RESISTANCE vs GATE VOLTAGE

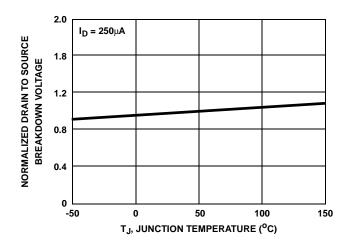
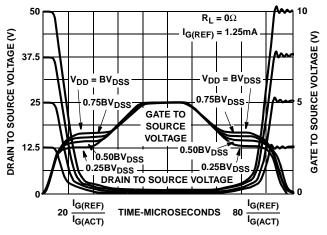


FIGURE 10. NORMALIZED DRAIN TO SOURCE BREAKDOWN VOLTAGE vs JUNCTION TEMPERATURE



NOTE: Refer to Fairchild Application Notes AN7254 and AN7260.

FIGURE 12. NORMALIZED SWITCHING WAVEFORMS FOR CONSTANT GATE CURRENT

Test Circuits and Waveforms

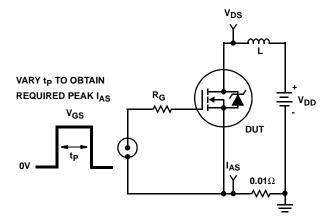


FIGURE 13. UNCLAMPED ENERGY TEST CIRCUIT

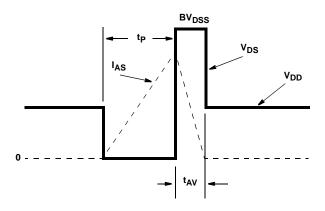


FIGURE 14. UNCLAMPED ENERGY WAVEFORMS

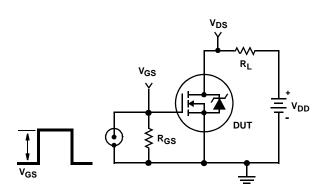


FIGURE 15. SWITCHING TIME TEST CIRCUIT

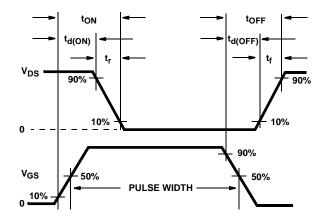


FIGURE 16. RESISTIVE SWITCHING WAVEFORMS

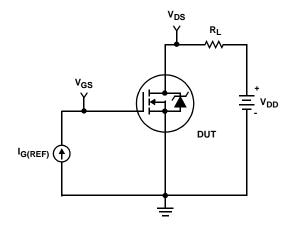


FIGURE 17. GATE CHARGE TEST CIRCUIT

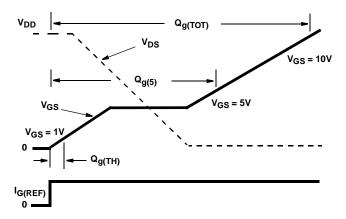


FIGURE 18. GATE CHARGE WAVEFORMS

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	EnSigna™	<i>i-</i> Lo [™]	OCX^{TM}	RapidConnect™	UHC™
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